



CHROcodile M15 – 5 Channel Optical Sensor Contactless measurement of wafers & solar cells



CHROcodile

If time matters...

Sensor Properties

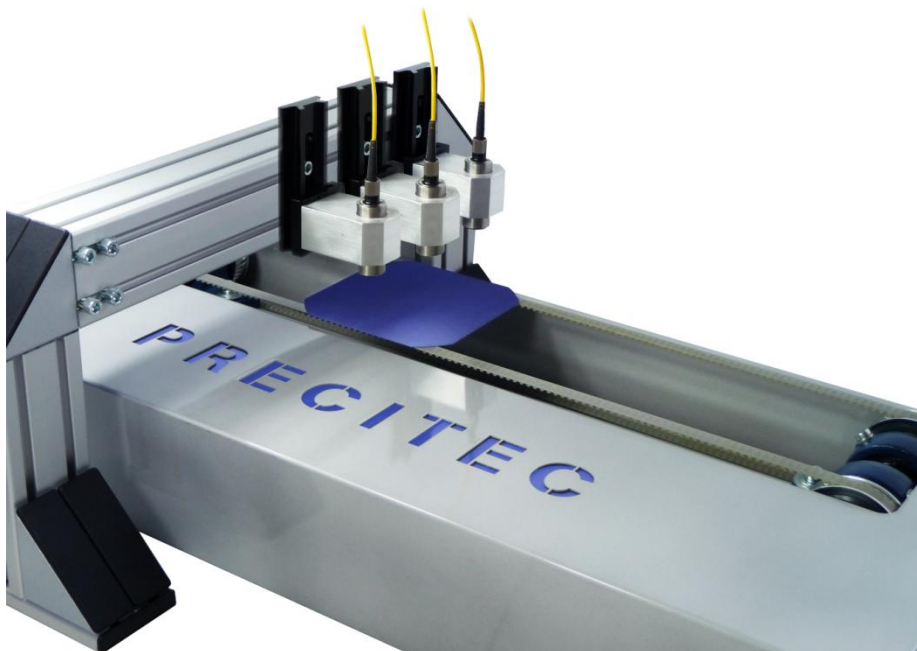
Further Information:
www.CHROcodile.com

- Up to 5 measuring channels
- High accuracy (in Si): down to 70 nm *
- High measuring rate: 4,000 Hz
- Lateral resolution: 6.5 μm
- Si-thickness: 7 μm to 1 mm
- Z-resolution: down to 1 nm *
- Measurement also of GaAs
- Transparent coatings/foils from 17 μm up to 2.3 mm
- Robust optical probe without electronics or light source

*depends on used measuring range

The new **CHROcodile MI5** is the modular 5 channel version of the already well established CHROcodile IT sensor. It performs high-precision, non-contact distance and layer thickness measurements on wafer and solar cells at up to 5 different locations. With one optical probe per channel, it is capable of measuring up to 1 mm thick silicon from one side. Measurements can also be taken on other common infrared transparent materials, such as GaAs.

The basis for this nondestructive measuring method is an interferometric sensor which examines the substrate with infrared light. The **CHROcodile MI5** is designed for simple and direct integration into the production process. One possible application is the inline thickness measurement of Si-wafers on a conveyor belt.



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